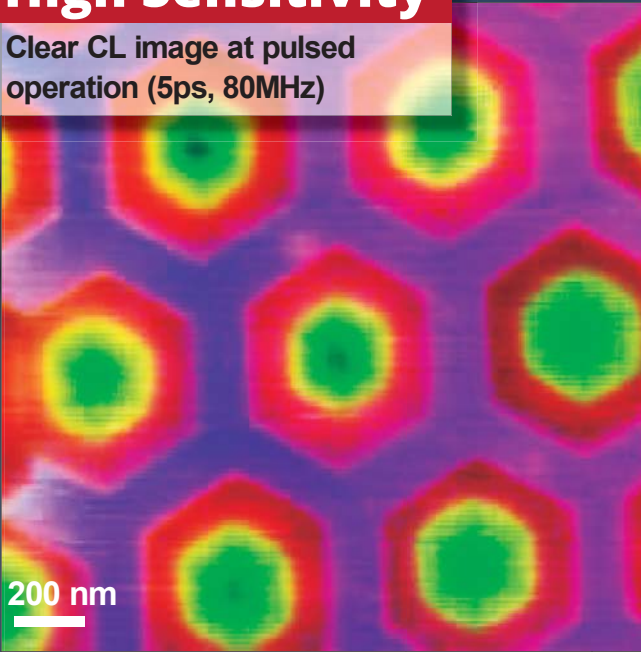
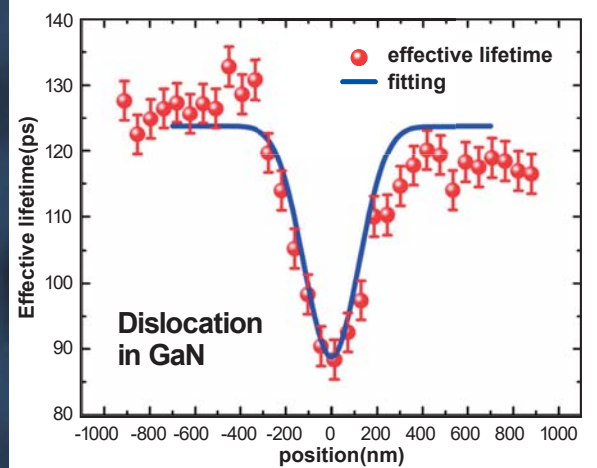


## High Sensitivity

Clear CL image at pulsed operation (5ps, 80MHz)



Nanowire-based LEDs (InGaN/GaN)



## Carrier dynamics observation in nm spatial resolution

Easy observation on site dependence of exciton lifetime

## Carrier dynamics observation in nanometer spatial resolution Local analysis on a single dislocation

### SEM-CL Fully Integrated System

## Pico-second time-resolved Cathodoluminescence Microscope



### FEATURES

- SEM-CL fully integrated system, easy operation
- 10 ps pulsed electron gun (1 pA~10 nA) CW/pulsed mode exchangeable
- High sensitivity CL optical system with no alignment
- Easy post processing due to high speed spectrum mapping
- 20 ~ 300 K, 6 axis low temperature stage

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